## **Annex B**

**Spectrum Data** 

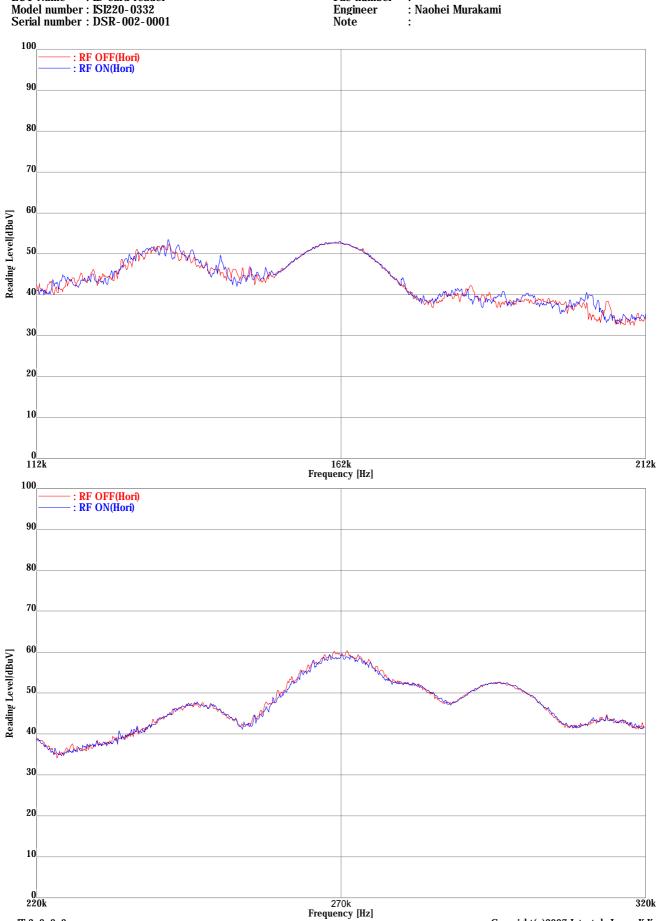
< Graph number #1 > SPECTRUM ANALYSIS

Distance 0.00 m 22.0°C /42.0%

Nagano No.3 Test Site
Date tested : Feb 04 2011
Company : NIDEC SANKYO CORPORATION Test mode : Continuous test mode Power source : AC120 V, 60 Hz

**EUT Name** : ID card reader File number

**Engineer** Naohei Murakami



emiT 3, 0, 0, 0

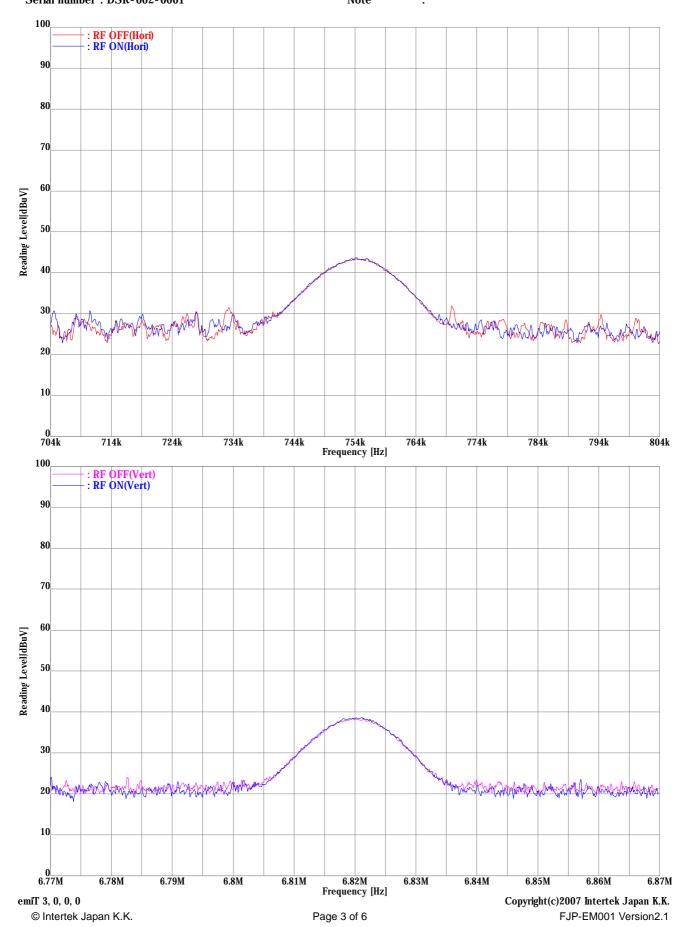
< Graph number #1 > SPECTRUM ANALYSIS

Nagano No.3 Test Site Distance 0.00 m 22.0°C /42.0%

Date tested : Feb 04 2011 Company : NIDEC SANKYO CORPORATION : Continuous test mode Test mode

Power source: AC120 V, 60 Hz : ID card reader **EUT Name** File number

Model number: ISI220-0332 **Engineer** Naohei Murakami Serial number: DSR-002-0001 Note



< Graph number #1 > SPECTRUM ANALYSIS

Nagano No.3 Test Site

Date tested : Feb 04 2011 Company : NIDEC SANKYO CORPORATION

: ID card reader **EUT Name** 

Model number: ISI220-0332

Serial number: DSR-002-0001

Distance 3.00 m 22.0°C /42.0%

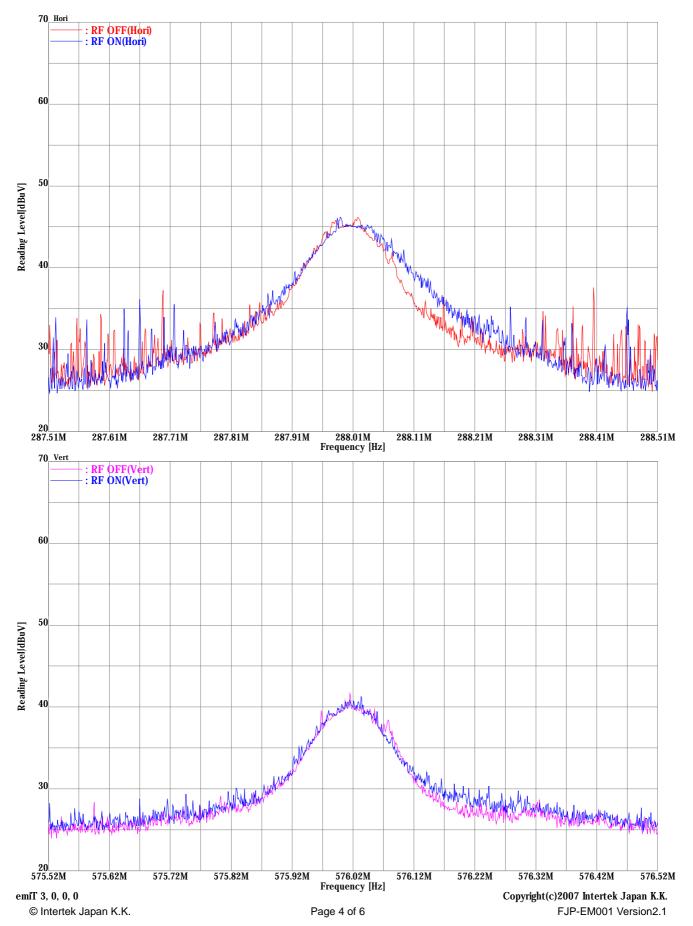
: Continuous test mode Test mode

Power source : AC120 V, 60 Hz

File number

Engineer Naohei Murakami

Note



< Graph number #1 >

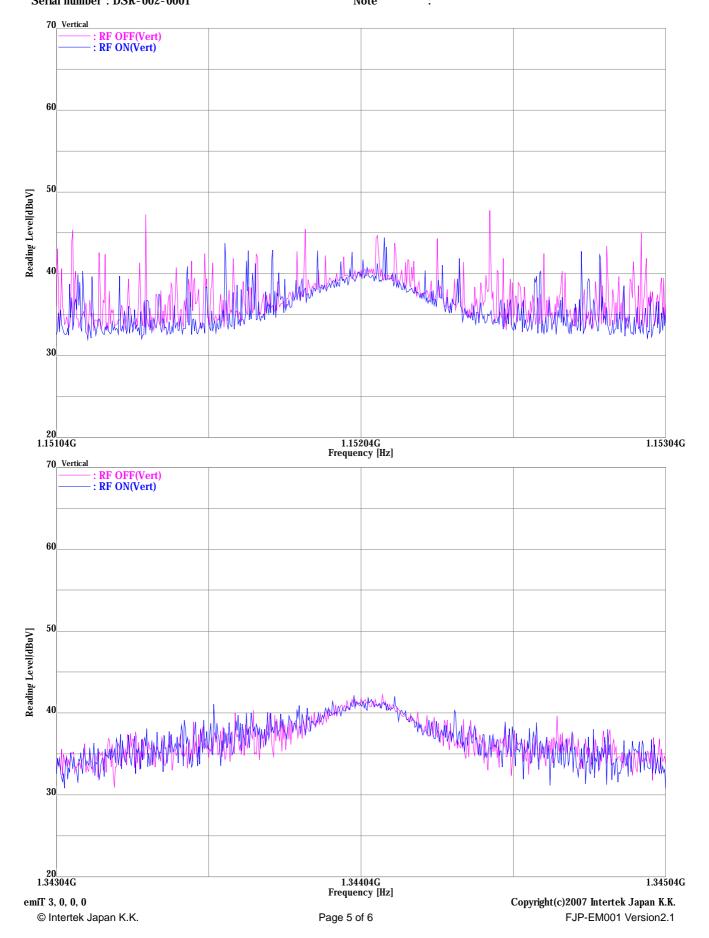
SPECTRUM ANALYSIS

Nagano No.3 Test Site Distance 0.00 m 18.0°C /32.0%

Date tested : Feb 04 2011 Company : NIDEC SANKYO CORPORATION : Continuous test mode Test mode

Power source : AC120 V, 60 Hz **EUT Name** : ID card reader File number

Model number: ISI220-0332 Serial number: DSR-002-0001 Engineer Naohei Murakami Note



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< Graph number #1 > SPECTRUM ANALYSIS

Distance 0.00 m 18.0°C /32.0%

Nagano No.3 Test Site
Date tested : Feb 04 2011
Company : NIDEC SANKYO CORPORATION : Continuous test mode Test mode

Power source : AC120 V, 60 Hz **EUT Name** : ID card reader File number

Model number: ISI220-0332 Serial number: DSR-002-0001 Engineer Naohei Murakami Note

